Hybrid 6p43 Traveler

January 7, 2000

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 6P43 has die: 194-077 194-078 194-079 194-080 194-081 194-083

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 6p43 classification info. Created 14:00:22 01/07/00

Hybrid 6p43 quality: fair
Chip classification: fair fair fair good fair fair
Bad channels (chip-channel): 1-67 4-39 5-124
Bad cells: none
Random bad capacitors (chip-cell-channel): 0-22-60 2-0-37 2-1-120
   2-22-37 2-30-49 2-39-37 2-42-37 2-44-37 2-44-53 2-9-36 2-9-37
Channels at pedestal needed for DCMS: 32.6 30.7 36.7 31.6 31.7 32.5
```

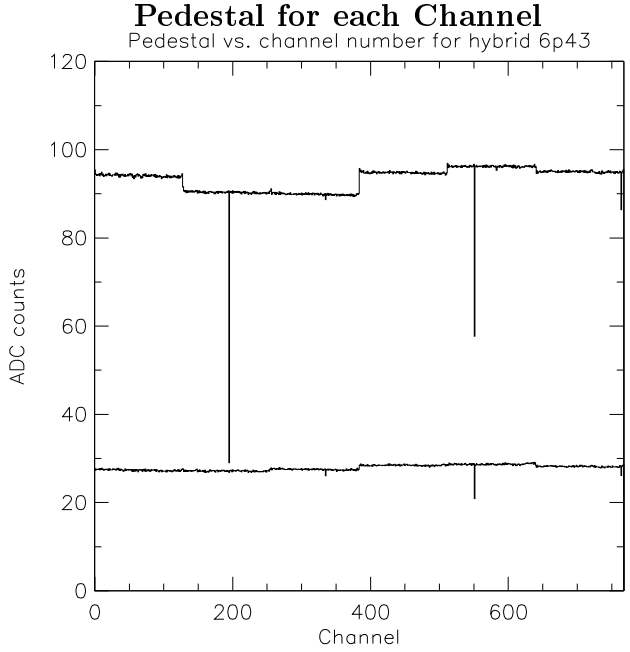
4 Comments

Has Au FE DVDD, DGND bonds.
HV test.

5 Pedestal

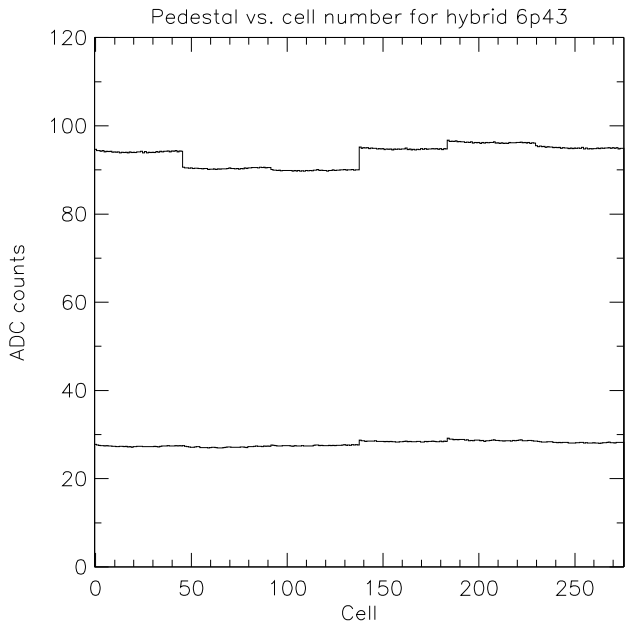
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

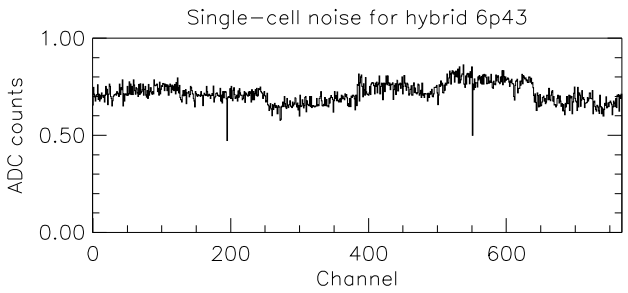
Pedestal vs. Pipeline Cell ID

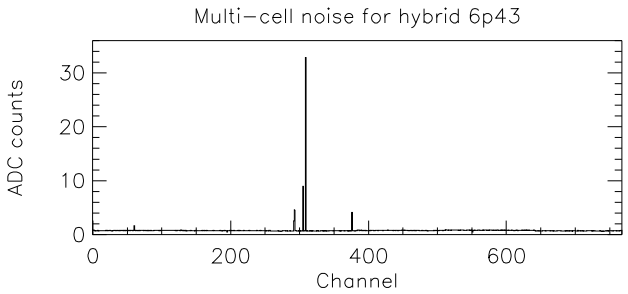


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

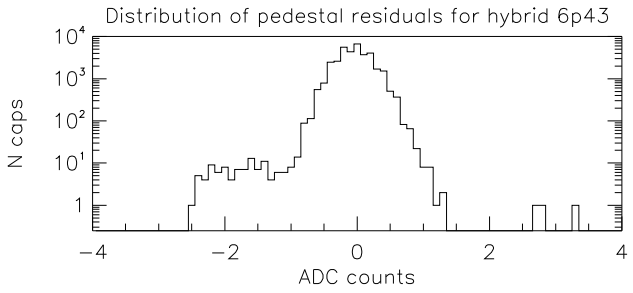
RMS Noise

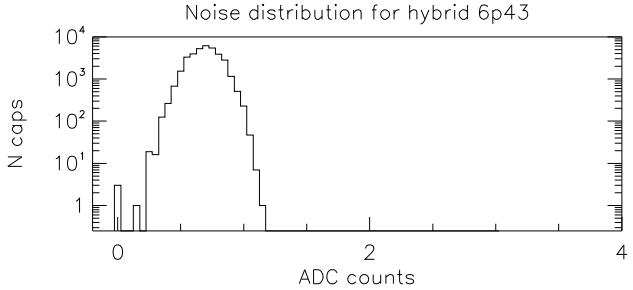




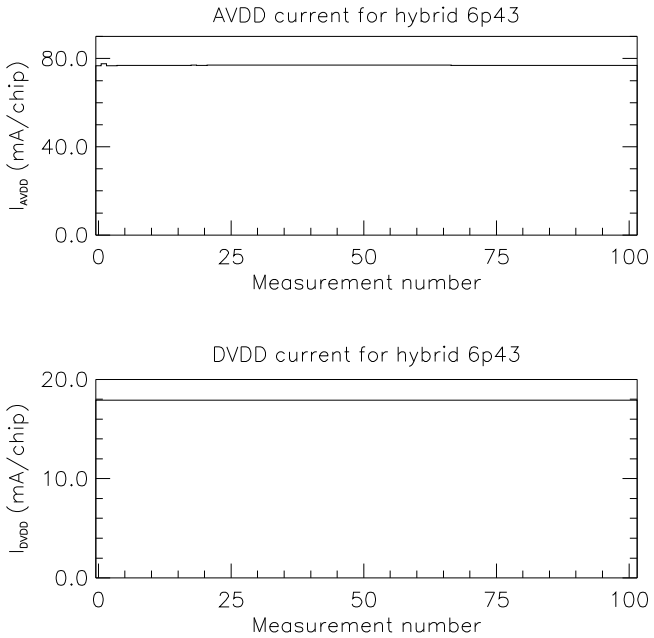
The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in